

Outline: ATPG for stuck at faults

- Deterministic, Fault-Oriented ATG
 - ◆ D-Algorithm
 - ◆ PODEM
 - ◆ FAN
- Random ATG
 - ◆ Weighted random
 - ◆ RAPS
- Test Compaction

D-Algorithm

- Roth (1966) proposed a D-algebra and a deterministic ATG algorithm.
 - ◆ D: good value 1 / faulty value 0
 - ◆ D: good value 0 / faulty value 1

5-valued algebra:

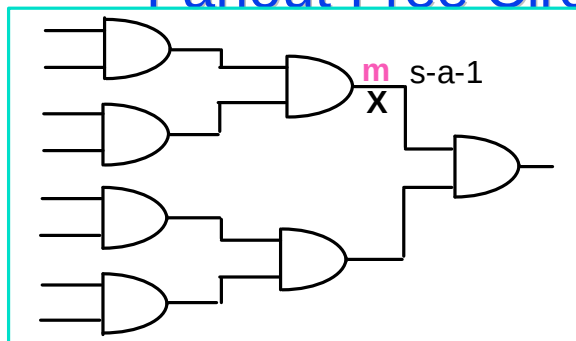
V_G / V_F	
0/0	0
1/1	1
1/0	D
0/1	D
-/X,X/-	X

D-Algorithm: 5-Valued Operations

	<table><tr><th>A</th><th>B</th><th>C</th></tr><tr><td>0</td><td>-</td><td>0</td></tr><tr><td>-</td><td>0</td><td>0</td></tr><tr><td>1</td><td>1</td><td>1</td></tr><tr><td>1</td><td>X</td><td>X</td></tr><tr><td>X</td><td>1</td><td>X</td></tr><tr><td>D</td><td>1</td><td>D</td></tr><tr><td>1</td><td>D</td><td>D</td></tr><tr><td>D</td><td>D</td><td>D</td></tr><tr><td>D</td><td>1</td><td>D</td></tr><tr><td>D</td><td>X</td><td>X</td></tr><tr><td>D</td><td>D</td><td>D</td></tr></table>	A	B	C	0	-	0	-	0	0	1	1	1	1	X	X	X	1	X	D	1	D	1	D	D	D	D	D	D	1	D	D	X	X	D	D	D	
A	B	C																																				
0	-	0																																				
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AND	0	1	D	$\bar{D}$	X
0	0	0	0	0	0
1	0	1	D	$\bar{D}$	X
$\bar{D}$	0	D	D	0	X
D	0	D	0	D	X
X	0	X	X	X	X

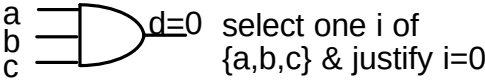
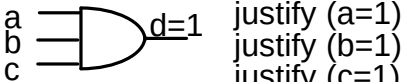
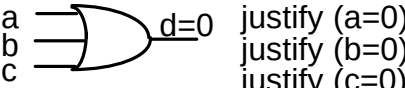
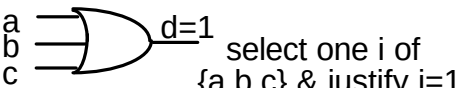
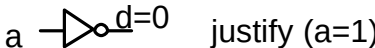
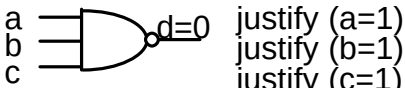
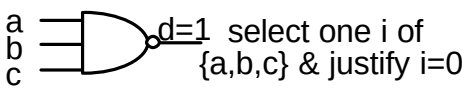
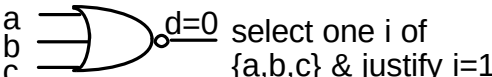
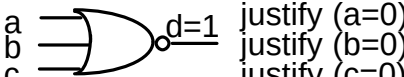
Fanout-Free Circuit



no conflicts with
implications or
justifications

- Test for **m** s-a-1 in a fanout-free circuit
 - begin**
 - set all lines to X;
 - Justify (**m**, 0); # activate the fault
 - Propagate (**m**, D);
 - end**

Justify

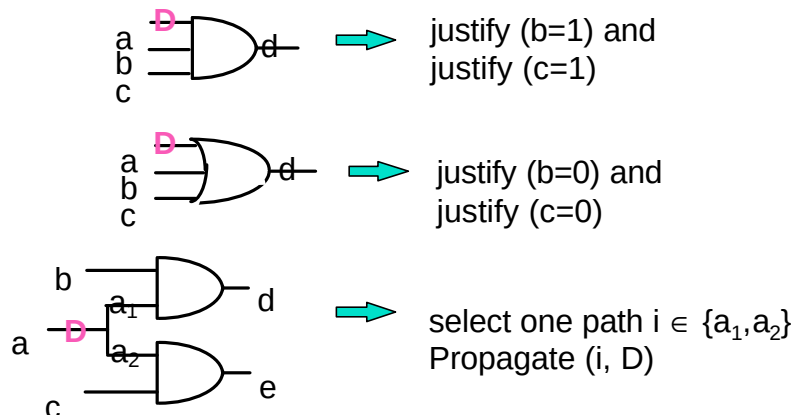
Justify d=0	Justify d=1
	
	
	
	
	

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Propagate (a, D)

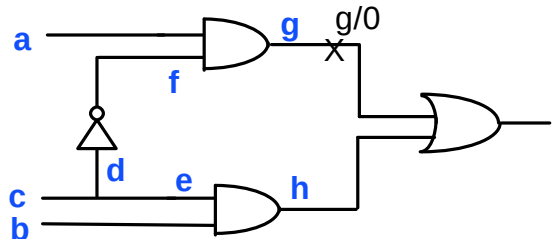
Propagate **D** on line **a**



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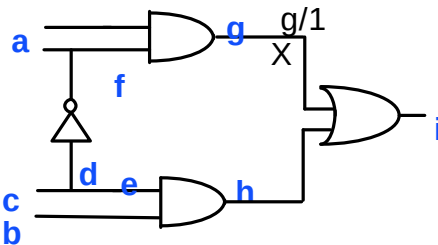
Test Generation



Set $g=1$
 justify ($g=1$)
 justify ($a=1$), justify ($f=1$)
 justify ($d=0$), $\rightarrow$ justify ($c=0$)
 propagate (g, D)
 justify ($h, 0$)
 $\rightarrow$ select one, justify ($e=0$) $\rightarrow$ justify ($c=0$)

Test Generation

- What if we make “wrong” selection (decision)?
- What if **justify ($a=1$)** fails?
- What if **propagate** fails?

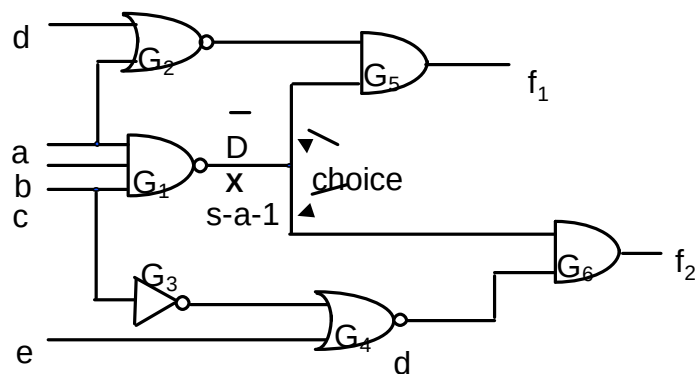


Set $g=0$
 justify ($g=0$)
 select $f \rightarrow$ justify ($f=0$)
 justify ($d=1$)
 justify ($e=1$)
 propagate (g, D)
 justify ($h, 0$)
 select e
 justify ($e=0$)
 justify ($c=0$) **X**

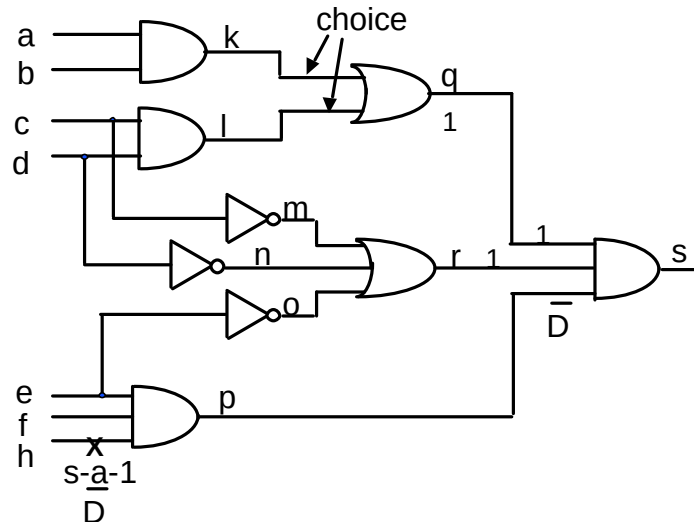
Backtracking

- Conflicts can occur in circuits with fanout and reconvergence.
 - ◆ If a decision causes inconsistency, then we need to backtrack.
 - ◆ A backtracking strategy is simply a systematic exploration of all decisions (choices).
 - ◆ Conflict/inconsistency/contradiction
 - ▲ An already-assigned value is different from the value implied by the last decision.
 - ◆ Bounding conditions
 - ▲ There is no D left in the circuit.
 - ▲ The fault is not excited.
 - ▲ Lookahead indicates that a D cannot propagate.

Choice in D-Propagation



Choice in Line Justification



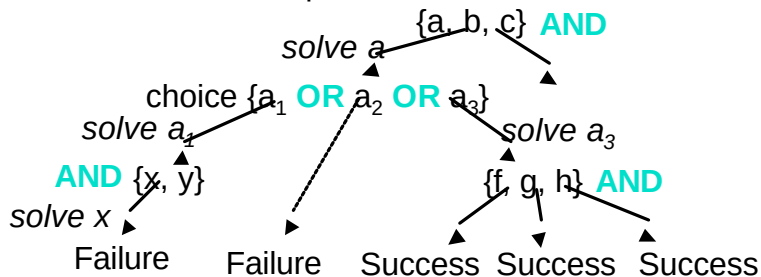
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General Test Generation Algorithm

- Procedure `ImPLY_and_check()` implies and checks for inconsistency.
- Procedure `Solve()` is a generic branch-and-bound procedure.
 - ♦ **AND-OR search strategy.**

set of problems that must be solved



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